

Excellence in Nanometrology

Analysis of coating layers and defects using Atomic Force Microscopy

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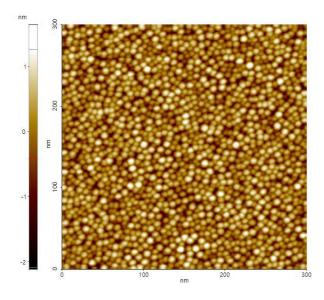


Figure 1: Non-contact image of a substrate before coating. The 300nmx300nm image allows for quantification of surface roughness before further material processing steps.

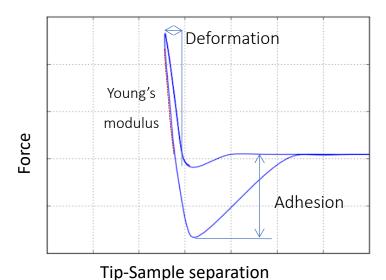


Figure 2: PinPoint nanomechanical mode is based on a fast force curve, displayed above. By ramping the tip vertical to the sample surface important mechanical information can be extracted with nanometer lateral resolution.